		,		-		
	Туре	Hits	Search Text	DBs	Time Stamp	Comments
H	BRS	8	<pre>improv\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)</pre>	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
2	BRS	2	l with or adj ited adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
ო	BRS	18	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:47	
. 7	BRS	, ,	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with processing with system\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	•

	Type	Hits	Search Text	DBs	Time Stamp	Comments
വ	BRS	m	edge\$1 with me (DUT or lj under adj (integrated adj r IC\$1) and rital with	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
9	BRS	. · · · · · · · · · · · · · · · · · · ·	with edge\$1 with 1\$1 same (DUT or 9\$1 adj under adj with (integrated adj it\$1 or IC\$1) and or (data or digit\$2) process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	·
	BRS	0	\$1 with DUT or der adj egrated adj \$1) and r digit\$2) and comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
· •	BRS	ഹ	adj \$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	
	BRS	M	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30	
10	BRS	33	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	

	- 1					
• .,	Туре	Hits	Search Text	DBs	Time Stamp	Comments
11	BRS	4	edge\$1 same vice\$1 adj under with (integratec t\$1 or IC\$1) anc ata or digit\$2) ss\$3) and	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	
12	BRS	4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and accurac\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
13	BRS	21	tim\$3 with edge\$1 same accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:45	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
14	BRS	13	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	
15	BRS	6	\$1 with DUT or der adj egrated adj \$1) and r digit\$2) and gnal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
16	BRS	10	with edge\$1 with c\$3 and (DUT or \$1 adj under adj with (integrated adj t\$1 or IC\$1) and r (data or digit\$2) rocess\$3) and 1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	·

	Type	Hits	Search Text	DBs	Time Stamp	Comments
17	BRS	1	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:53	
18	BRS	12	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	

	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
			(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or			
19	BRS	4.	adj under adj h (integrated adj) or IC\$1) and	US-PGPUB; USPAT; EPO; JPO; DERWENT;	2006/03/27 11:02	
· ·			(DFS Or (data or digit\$2) J with process\$3) and cycle\$1 with tim\$3 and instruct\$3	IBM_TDB		
50	BRS	S	m\$3 with edge\$1 and \$3 and (DUT or adj under adj ith (integrated adj ith (integrated adj \$1 or IC\$1) and (data or digit\$2) ocess\$3) and with tim\$3 and	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
			error\$1		·	

•	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
21	BRS	12	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
22	BRS	15	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
8 8	BRS	O ,	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:05	
24	BRS	4	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

<u>.</u>	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
,			(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1			
			(integrated		•	
			uit\$1 or I			
			(DPS or (data or digit\$2)			
			with process\$3) and	US-PGPUB;	·	
25	RRS	. 7	with tim\$3 and	USPAT; EPO;	2006/03/27	
) L		†	clock\$1 and (DUT or	JPO; DERWENT;	11:07	
				IBM_TDB		
			test) and (reference\$1 or			
			threshold\$1 or desired or			
			expected or predefined or			
			term			
			with tim\$3			
			\$3 or 8			
			with tim\$3 with edg\$3 same			
	•		(integrated adj circuit\$1			
			or IC\$1) and (DPS or (data			
) with	י פוזפטפ - אוז		
			and cycle\$1		60/00/000	
5 6	BRS	4	and clock\$1 and	USKAI; EFU; TDO: DEDMENTE.	Z006/03/2/	
			(DUT or device\$1 adj under	OFO, DEKWENT;	80:11	
. -						
			or threshold\$1 or desired			
			or expected or predefined			
			or predetermined or			
			preset\$4) with tim\$3			
					I	

TY	Type Hits	Search Text	DBs	Time Stamp	Comments
27 BRS	28	(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
80 7	BRS	20	(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3 and computer\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
29	BRS	9747	702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM IDB	2006/03/27 11:10	
30	BRS ,		<pre>improv\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)</pre>	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
31	BRS	8	ih adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
32	BRS	19.	th r dj ed adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
33	BRS		or desired) with same (DUT or adj under adj h (integrated adj or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:49	
34	BRS	2	20060036	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 09:58	
35	BRS		tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with processing with system\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
36	BRS	m .	edge\$1 with me (DUT or ij under adj (integrated adj r IC\$1) and ital with	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
37	BRS	- 8	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
88	BRS	0	\$1 with DUT or der adj egrated adj \$1) and r digit\$2) and comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:11	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
		·	(compar\$4 or differen\$2) with tim\$3 with edge\$1			
			with signal\$1 with			
			(threshold\$1 or		,	
			reference\$1 or expected or			
			desired or predetermined	US-PGPUB;		-
39	BRS		preset\$4 or predefined)	USPAT; EPO;	2006/03/27	
))		or device\$1 adj	JPO; DERWENT;	10:15	
			j test) with	IBM TDB		
			(integrated adj circuit\$1			
_			Ю			
			or digit\$2) with			,
			process\$3) and (calculat\$3			i.
			or comput\$3) with error\$1			·
<u>.</u>	•	,	th			
			signal\$1 with (threshold\$1			
			or reference\$1 or expected			
			or desired or	US-PGPUB;		
O V	ממ	,-	preset\$4	USPAT; EPO;	2006/03/27	
) !'	2	٠.	predefined) same (DUT	JPO; DERWENT;	10:17	
			r device\$1 adj under adj	IBM_TDB		
			test) with (DPS or (data			
			or digit\$2) with			
			process\$3)			-

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
	·			·		
			th			
			signal\$1 with (threshold\$1			
			or reference\$1 or expected	. מזזמיטם יי		
			or desired or			
41	BRS	5.6	predetermined or preset\$4	USFAL; EFU;	70/00/03/2/	
			or predefined) same (DUT	OPO; DEKWENI;	07:01	
			or device\$1 adj under adj		• .	
			test) and (DPS or (data or			
			digit\$2) with process\$3)			
			tim\$3 with occurrence\$1	US-PGPUB;		
2	טפם	-	with edge\$1 with signal\$1	USPAT; EPO;	2006/03/27	
7	247	4	with (DUT or device\$1 adj	JPO; DERWENT;	10:21	
			under adj test)	IBM TDB		
			(threshold\$1 or	•		
			reference\$1 or expected or			
			desired or predetermined	US-PGPUB;		
٧٦	ממ	α	or preset\$4 or predefined)	USPAT; EPO;	2006/03/27	
) יי		o	with tim\$3 with point\$1	JPO; DERWENT;	10:26	
			\$1	IBM TDB		
	,		same (DUT or device\$1 adj			
.			under adj test)			

	Type	Hits	Search Text	DBs	Time Stamp	Comments
44	BRS	39	or expected or predetermined or predefined) with point\$1 with signal\$1 device\$1 adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
4 ت	BRS	2	(determin\$3 or calculat\$3 or computing or comput or computa) with (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
46	BRS	 	3 with edge\$1 with al\$1 same (DUT or ce\$1 adj under adj) with (integrated adj uit\$1 or IC\$1) and or (data or digit\$2) process\$3) and culat\$3 or comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
47	BRS	M	edge\$1 with ame (DUT or dj under adj (integrated adj or IC\$1) and ata or digit\$2) ss\$3) and	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30	
48	BRS	М	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	
49	BRS	4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	

	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
50	BRS	4	edge\$1 same vice\$1 adj under with (integrated t\$1 or IC\$1) and ata or digit\$2) ss\$3) and	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
51	BRS	23	edge\$1 same and (DUT or dj under adj (integrated adj or IC\$1) and ata or digit\$2) ss\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:46	
52	BRS .	40	tim\$3 with edge\$1 same occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:49	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
53	BRS	2.4	ith adj ted adj and git\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
54	BRS	. 0	with tim\$3 with th occur\$6 and evice\$1 adj under with (integrated it\$1 or IC\$1) and data or digit\$2) ess\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
55	BRS	₽	compar\$4 same tim\$3 with edge\$1 with occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
56	BRS	14	with T or r adj rated adj) and digit\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	
57	BRS	10	edge\$1 with and (DUT or dj under adj (integrated adj or IC\$1) and ata or digit\$2) ss\$3) and th signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
28	BRS	11	ch dj ed adj nd it\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	

ı	Туре	Hits	Search Text	DBs	Time Stamp	Comments
			(calibrat\$3 or adjust\$3)			
			with tim\$3 with edge\$1			
			with accurac\$3 and (DUT or	. מוזמיטת מו		-
		,	device\$1 adj under adj	J.S F.G.F.O.B.;		
59	BRS	2	test) with (integrated adj	USFAI; EFU;	77/50/03/7/	
			circuit\$1 or IC\$1) and	OFO, DEKWENI,	70:28	
			(DPS or (data or digit\$2)	15M 1DB	-	š
			with process\$3) and			·
			cycle\$1 with tim\$3			
			(calibrat\$3 or adjust\$3 or			
			compensat\$3) with tim\$3			
			with edge\$1 with accurac\$3			
			and (DUT or device\$1 adj	JS-PGPUB;		
9	ממ		test) with	JSPAT; EPO;	2006/03/27	
	270	7		JPO; DERWENT;	10:59	
			nd (DPS or (data	IBM TDB		
			or digit\$2) with	l		
			process\$3) and cycle\$1	-		
			with tim\$3	·		

	Туре	Hits	Search Text	DBs	Time Stamp Comments	Comments
61	BRS	13	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
62	BRS	2	at\$3 or adjust\$3) m\$3 with edge\$1 and \$3 and (DUT or 1 adj under adj ith (integrated adj \$1 or IC\$1) and (data or digit\$2) ocess\$3) and with tim\$3 and t\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
63	BRS	13	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with tim\$3 and (DUT or device\$1 adjunder adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
64	BRS	5	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with tim\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and instruct\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
65	BRS	6	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
99	BRS	6	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with tim\$3 and (DUT or device\$1 adjunder adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
·			(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and			
			accurac\$3 and (DUT or device\$1 adj under adj	US-PGPUB;	· ·	
67	BRS	13	test) with (integrated adj	USPAT; EPO;	2006/03/27	
			data or digit\$2)	JEO, DERWENI; IBM TDB	11:03	
			5\$3	I		
			cycle\$1 with tim\$3 and			
			clock\$1			
			(calibrat\$3 or adjust\$3 or			
			compensat\$3) with tim\$3			
		. •	with edge\$1 and accurac\$3			
			and (DUT or device\$1 adj	US-PGPUB;		
89	R S S	13	under adj test) with	USPAT; EPO;	2006/03/27	
)	ted adj circuit\$1	JPO; DERWENT;	11:04	
			and (DPS or (data	IBM TDB		
		•	or digit\$2) with	ľ		
			process\$3) and cycle\$1			
		,	with tim\$3 and clock\$1			

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
69	BRS	17	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
70	BRS (0	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 US-PGPUB; or IC\$1) and (DPS or (data USPAT; EPO; or digit\$2) with process\$3) and cycle\$1 IBM_TDB with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) (calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or IC\$1) and (DPS or (data or IC\$1) and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3		Туре	Hits	Search Text	DBs	Time Stamp	Comments
with edge\$1 same (integrated adj circuit\$1 US-PGPUB; or IC\$1) and (DPS or (data USPAT; EPO; or digit\$2) with process\$3) and cycle\$1 IBM_TDB with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) (calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or IC\$1) and cycle\$1 brocess\$3) and cycle\$1 brocess\$3) and cycle\$1 brocess\$3) and cycle\$1 cor digit\$2) with brocess\$3) and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or breset\$4) with tim\$3				ibrat\$3 or adjust\$3 ensat\$3) with tim\$3			
BRS 5 or IC\$1) and (DPS or (data USPAT; EPO; or digit\$2) with UPO; DERWENT; process\$3) and cycle\$1 IBM_TDB with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) (calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with tim\$3 with clock\$1 and (DPS or (data or IC\$1) and (DPS or (data or IC\$1) and (DPS or (data or digit\$2) with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or predefined or predetermined or breset\$4) with tim\$3				edge\$1 same			
process\$3) and cycle\$1 process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) (calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or IC\$1) and cycle\$1 brocess\$3) and cycle\$1 USPAT; EPO; with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	Ţ	, ,		rated adj circuit\$1 1) and (DPS or (data	JS-PGPUB; JSPAT: FPO:	70/80/9006	
process\$3) and cycle\$1 IBM_TDB with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) (calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 BRS by with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or expected or predefined or predetermined or breset\$4) with tim\$3	1/	BKS		it\$2) with	TPO; DERWENT;	11:07	
with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) (calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 or digit\$2) with (DUT or device\$1 adj under (DUT or device\$1 adj under (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or expected or predefined or predetermined or preset\$4) with tim\$3				s\$3) and cycle\$1	BM_TDB		
(DUT or device\$1 adj under adj test) (Calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or expected or predefined or predetermined or preset\$4) with tim\$3				im\$3 and clock\$1	.		
adj test) (calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3		٠.		(DUT or device\$1 adj under			
(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or IC\$1) and (DPS or (data or IC\$1) and cycle\$1 brocess\$3) and cycle\$1 with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or predetermined or creates or predetermined or preset\$4) with tim\$3				adj test)			
compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3				or adjust\$3			
with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3				compensat\$3) with tim\$3			
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or IC\$1) and (DPS or (data or digit\$2) with US-PGPUB; process\$3) and cycle\$1 USPAT; EPO; with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or predetermined or predetermined or predetermined or preset\$4) with tim\$3				(integrated adj circuit\$1			
Drocess\$3) and cycle\$1 BRS 5 with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or expected or predefined or predetermined or preset\$4) with tim\$3				or IC\$1) and (DPS or (data			
BRS 5 with tim\$3 and cycle\$1 USPAT; EPO; with tim\$3 and clock\$1 and UPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or breset\$4) with tim\$3				or digit\$2) with	JS-PGPUB;	:	
with tim\$3 and clock\$1 and JPO; DERWENT; (DUT or device\$1 adj under IBM_TDB adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3				ss\$3) and cycle\$1	SPAT; EPO;	2006/03/27	
T or device\$1 adj under test) and (reference\$1 threshold\$1 or desired expected or predefined predetermined or				cim\$3 and clock\$1 and	PO; DERWENT;	11:07	
test) and threshold\$1 expected or predetermin			1	or device\$1 adj under.	BM TDB		
threshold\$1 expected or predetermin				test) and			
expected or predetermine eset \$4) with				r threshold\$1	٠		
predete				r expected or			
reset\$4)				predete			
/				preset\$4) with tim\$3	•		

	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
. ,			(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with eda\$3 same			
			σ σ			
		·	\$2) with 3) and cycle\$1	US-PGPUB; USPAT: EPO:	70/80/9002	
73	BRS	<u>.C</u>	and clock\$1 and	JPO; DERWENT;	11:08	
			(DUT or device\$1 adj under IBM_TDB	IBM_TDB	٠	
		·.	adj rest, and (referencesi or threshold\$1 or desired			
			or expected or predefined			
		-ii	Ψ		•	
			preset\$4) with tim\$3			

	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
			(calibrat\$3 or adjust\$3 or			
			with edg\$3 and test\$3 with			
•			(integrated adj circuits1 or ICS1) and (DPs or (data		-	
			digit\$2	US-PGPUB;		
74	BRS	32		USPAT; EPO;	2006/03/27	
				JPO; DERWENT;	11:09	
			(DUT or device\$1 adj under IBM_TDB	IBM_TDB		
			adj test) and (reference\$1			
			or threshold\$1 or desired			
			or expected or predefined			
	٠.		or predetermined or	·.		
			preset\$4) with tim\$3			

	Type	Hits	Search Text	DBs	Time Stamp	Comments
			alibrat\$3 or adjust\$mpensat\$3) with tim\$			
			with edgas and testas with (integrated adj circuit\$1 or IC\$1) and (DPS or (data			·
75	BRS	24		US-PGPUB; USPAT; EPO;	2006/03/27	
		· · ·	or device\$1 adj under est) and (reference\$1	JPO; DERWENT; IBM_TDB	11:09	
		·	or threshold\$1 or desired or expected or predefined			
			(1)			
		•	7			
			(702/57,69.ccls. or 714/724,742,744.ccls. or			
9/	BRS	18	4/158.1.ccls.) and tim\$3 th point\$1 with edge\$1	US-PGPUB; USPAT; EPO; IDO: DFDWENT.	2006/03/27	
			signal\$1 and (DUT or ce\$1 adj under adj	IBM_TDB	0 1	
			resr)			

	Type	Hits	Search Text	DBs	Time Stamp	Comments
77	BRS	9		US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
78	BRS	7	42,744.ccls. or .ccls.) and tim\$3 t\$1 with edge\$1 al\$1 with (DUT or adj under adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
79	BRS	112	h point\$1 with th signal\$1 and levice\$1 adj under	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:17	
80	BRS	% 7	(702/57,69,117.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:24	

	Type	Hits	1	DBs	Time Stamp	Comments
8 1	BRS	9 8	("702"/\$.ccls. or "714"/\$.ccls. or "324"/\$.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:19	
82	BRS	42	/57,69,117,119.ccls. 700,718,724,736,742,74 4,815.ccls. or 158.1.ccls.) and tim\$3 point\$1 with edge\$1 signal\$1 and (DUT or ce\$1 adj under adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:25	
8 8	BRS	2.43	r r 14/700,718,724,736,742,74 ,744,815.ccls. or 24/158.1.ccls.) and tim\$3 ith edge\$1 with signal\$1 nd (DUT or device\$1 adj nder adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
			59,117,119.ccls.	US-PGPUB;		
84	BRS	116		USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:25	
20 20	BRS	53	117,119.ccls. 724,736,742,74 cls. or	US-PGPUB; USPAT; EPO; JPO: DERWENT:	2006/03/27	
			s\$1 with signal\$1 or device\$1 adj	IBM_TDB] •	
9	BRS	ത	02/57,69,117,119.ccls. 4/700,718,724,736,742,74 744,815.ccls. or 4/158.1.ccls.) and tim\$3	US-PGPUB	2006/03/27 11:29	
Ì			with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)		·	

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
87	BRS	12	(count\$3 or occur\$6 or number\$1) with tim\$3 with edge\$1 with signal\$1 with [DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	
88	BRS	4	or differen\$2) \$3 or occur\$6) with tim\$3 with signal\$1 or device\$1 adj est)	US-PGPUB	2006/03/27 11:30	
6 8	BRS	43	(702/57,69,117,119.ccls. or 714/700,718,724,736,742,74 3,744,815.ccls. or 324/158.1.ccls.) and tim\$3 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 11:31	
06	BRS	170	h signal\$1 with ith cycle\$1 with	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:46	
91	BRS	7.0	generat\$3 with cycle\$ with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:47	

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
Ŋ	BRS	٥	generat\$3 with cycle\$ with edge with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27	
ю	BRS		generat\$3 with cycle\$ with edge with signal\$1 with (DUT or device adj under adj test\$3) or tester\$1) with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:50	
4	BRS	12	(count\$3 or occur\$6 or number\$1) with tim\$3 with (peak\$1 or edge\$1) with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	4.
. ഹ	BRS		compar44 with expected with tim\$3 with edge with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 12:55	
9	BRS	40	compar\$4 with expected with tim\$3 with edge with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 12:55	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
97	BRS		compar\$4 with expected with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
86	BRS	3	compar\$4 with (desired or expected) with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
66	BRS	~	(differen\$2 or compar\$4) with (desired or expected) with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
100	BRS	10	en\$2 or compar\$4) esired or expected) a\$3 with edge\$1 ynal\$1 and (DUT or adj under adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:08	
101	BRS	126	tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 13:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
102	BRS	14	(adjust\$3 or calibrat\$3 or compensat\$3) with tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adjunder adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
103	BRS	0	3 or calibrat\$3 or t\$3) with tim\$3 e\$1 with signal\$1 ual same (DUT or adj under adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:15	
104	BRS	0	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired) adj tim\$3) same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	
105	BRS	0	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired) same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	

Search Text t\$5 or calibrat\$3 or sat\$3) with (tim\$5 uS-PGFUB; ge\$1) with signal\$1 uS-PGFUB; ge\$1 with (tim\$3 udefined or preset\$4 uS-PGFUB; ge\$1 with (tim\$3 udefined or preset\$4 uS-PGFUB; ge\$1) with (tim\$3 udefined or preset\$4 uS-PGFUB; ge\$1) with signal\$1 ush ush ush (ush ush ush ush ush ush (ush ush ush ush ush ush ush (ush ush ush ush ush ush ush (ush ush ush ush ush ush ush ush ush ush							
(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 us-pGPUB; adj edge\$1) with signal\$1 usPAT; EPO; with (expected or desired) JPO; DERWENT; and (DUT or device\$1 adj IBM_TDB under adj test\$3) (adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 usPAT; EPO; predefermined or preset\$4 usPAT; EPO; predetermined or preset\$4 uspat; EPO; predetermined or preset\$4 uspat; EPO; predetermined or preset\$4 under adj test\$3) (adjust\$3 or calibrat\$3 or calibrat\$3 or calibrat\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired uspat; EPO; predetermined or preset\$4 uspat; EPO; or reference\$1 or threshold\$1) with tim\$3 under adj threshold\$1) with tim\$3 under adj test\$3) with edge\$1 and (DUT or device\$1 adj under adj test\$3)		Type		Search Text	DBs	Time Stamp	Comments
(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired US-PGPUB; or predefermined or preset\$4 JPO; DERWENT; or reference\$1 or device\$1 adj under adj test\$3) (adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired or predefermined or preset\$4 or reference\$1 or predefined or preset\$4 JPO; DERWENT; or reference\$1 or predefined or with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test\$3)	106			ust\$3 or calibrat\$3 unsat\$3) with (tim\$3 edge\$1) with signal\$ (expected or desire DUT or device\$1 adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
(adjust\$3 or calibrat\$3 or compensat\$1) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired or predefined or preset\$4 or predetermined or preset\$4 or reference\$1 or threshold\$1) with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test\$3)	107	BRS	9	just\$3 or calibrat\$3 or pensat\$3) with (tim\$3 edge\$1) with signal\$1 h (expected or desired predefined or reference\$1 or eshold\$1) and (DUT or ice\$1 adj under adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:21	
	108			ust\$3 or calibrat\$3 ensat\$3) with (tim\$3 edge\$1) with signal\$ (expected or desired redefined or etermined or preset\$ eference\$1 or shold\$1) with tim\$3 edge\$1 and (DUT or ce\$1 adj under adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:23	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
109	BRS	o	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired or predefined or preset\$4 or reference\$1 or threshold\$1) with tim\$3 with tim\$3 and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:31	
110 BRS	,	m	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (tester\$1 or DUT or (device\$1 adj under adj test\$3)) with cycle\$1 with time\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:33	

	D	H	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieva 1
<u> </u>			US 2006004982 0 Al	20060309	17	Method and apparatus for remotely buffering test channels	324/158.1		324/158.
N	×		US 2006003172 8 A1	20060209	15	Method and apparatus for measuring digital timing paths by setting a scan mode of sequential storage elements	714/724		714/724
m	×		US 2006001035 8 Al	20060112	21	Method and apparatus for calibrating and/or deskewing communications channels	714/700	455/67.16 714/700	714/700
4	×		05026769 Al	20051201		urement rument a urement	702/57		702/57
ഗ	\sim	÷	US 2005024660 3 A1	20051103 1	12	Pin coupler for an integrated circuit tester	714/742		714/742
9	×		US 2005024660 1 A1	20051103		Method and apparatus to measure and display data dependent eye diagrams	714/724		714/724

	D	Н	Document ID:	Issue Date	Page s	Title	Current OR	Current XRef	Retrieva 1 Classif
7	×		US 2005022531 4 A1	20051013		Method of measuring duty cycle	324/158.1		324/158.
8	×		us 2005019335 5 Al	20050901	19	Source synchronous timing extraction, cyclization and sampling	716/6	703/19; 714/724	714/724
6	×		US 2005016033 1 A1	20050721		PICA system timing measurement and calibration	714/700		714/700
10	×	_ X	US 2005009742 0 A1	20050505	26	Apparatus for jitter testing an IC	714/742		714/742
11	×	-	US 2005008816 7 Al	20050428		Isolation buffers with controlled equal time delays	324/158.1		324/158. 1
12	×		US 2005008058 0 A1	20050414	27	Device for testing lsi to be measured, jitter analyzer, and phase difference detector	702/117		702/117
13	×		us 2005005041 20050303 1 A1	20050303		Pre-stored digital word generator	714/724		714/724

	D	1 Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieva l Classif
14	×	us . 2005003861 5 Al	20050217		Qualification signal measurement, trigger, and/or display system	702/69		702/69
15	×	US 2005003404 4 A1	20050210	25	Semiconductor test device and timing measurement method	714/742		714/742
16	×	US 2005002806 2 A1	20050203	2 10 77 14	Test method and apparatus for high-speed semiconductor memory devices	714/736		7.14/736
17	_×	US 2005002208 8 A1	20050127		Semiconductor tester 714/744	714/744		714/744
18	×	US 2005002208 1 A1	20050127	42	Test systems and methods with compensation techniques	714/724		714/724
19	×	US 2005002208 0 A1	20050127 43		d methods with test	714/724		714/724
20	×	US 2004026049 2 A1	20041223	6	tter of binary ata	702/69		702/69
							7	

	D	1 Document	Issue	Page	Title	Current	Current	Retrieva 1
		בַּי	חמרפ	מ		S.	AKer	Classif
21	×	US 2004015326 20040805	20040805		System and method of testing a	702/69	-	702/69
		7 A1	·		transceiver			
. (US	(d m			
ZZ	×	2004012260 7 Al	20040624		measuring a signal propagation delay	702/69		702/69
					1 41			
					arbitrary dynamic			
		.•		<i>-</i> -1	mappings to	٠,		
· .		US.			serialize vectors		,	
23	×	2004007874	20040422		into transmitted	714/718		714/718
		0 A1			sub-vectors and de-			
					serialize received	·		
			,	• •	sub-vectors into			
					vectors	,	,	
				•	Deskewed			
	-	SO			differential			711/700.
24	×	2004006476	20040401		detector employing	714/700	714/724	711/72/
		5 A1			analog-to-digital			F7//FT/
					converter			
L	, ,	US			speed tester	() () ()	.*	324/158.
ر 2	×	ZUU4UU5I5I 8 Al	Z00403I8		with narrow output pulses	324/158.1		·
		0.1			Instrument initiated		·	
26	×	2000000332	101010101		communication for	171117		11/1701
) 		20000 L \(\times \)	1 0 1 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0	· · · · ·	automatic test	F7//FT/		F7//FT/
		7.7			equipment			

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·	Þ	H	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieva 1 Classif
27	_×_		US 2003023360 4 A1	20031218		Memory device test system and method	714/718		714/718
28	\times	,	US 2003022946 6 A1	20031211		Test method and apparatus for source synchronous signals	702/117		702/117
29	×		US 2003015868 7 A1	20030821	11	Composite eye diagrams	702/117		702/117
30	_×		US 2003012653 0 A1	20030703	13	Time shift circuit for functional and AC parametric test	714/724		714/724
31	_×_		US 2003011712 9 A1	20030626	7	Low-cost tester interface module	324/158.1	324/765	324/158.
32	×		US 2003011042 7 A1	20030612		Semiconductor test system storing pin calibration data in non-volatile memory	714/724		714/724
33	×	×	US 2003002883 2 A1	20030206	18	uit	714/700		714/700
34	×	·	US 2003000537 5 Al	20030102		Algorithmically programmable memory tester with test sites operating in a slave mode	714/724		714/724

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			A	Date	Ŋ		OR R	XRef	Classif
<u>3</u> 2	×		US 2002018600 4 A1	20021212	<u> </u>	Method for manufacturing smart card and identification devices and the like	324/158.1		324/158.
36	× .		US 2002018458 1 Al	20021205		for testi ductor ch iconducto	714/724		714/724
37	×		US 2002017000 6 A1	20021114	17 1	Differential receiver architecture	714/724		714/724
38	×		US 2002015243 7 Al	20021017	<u></u>	Circuitry for and system and substrate with circuitry for aligning output signals in massively parallel testers and other electronic devices	714/724		714/724
39	×	×	US 2002013535 7 A1	20020926	14 t	Method and apparatus for socket calibration of integrated circuit testers	324/158.1		324/158.

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40	×	<u> </u>	us 2002012587 8 Al	20020912	7 7 0	High-frequency tester for semiconductor devices	324/158.1		324/158.
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42	×	Σ () ω	us 2002004289 8 Al	20020411	L. P 03 03 A	Test interface for verification of high speed embedded synchronous dynamic random access memory (SDRAM) circuitry	714/744	365/192	714/744
43	×	, D (V (V	us 2001001046 2 Al	20010802	<u> </u>	Carrier identification system, carrier identification method and storage media	324/158.1		324/158.